

Form PTO-1449

Sheet 1 of 1

Applicant: Junji Yumoto et al.

Confirmation No.: 8722

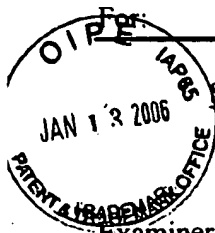
Serial No.: 10/531,485

Att'y Docket No.: 14321.69

Filing Date: April 15, 2005

Art Unit: 2828

For: LASER LIGHT SOURCE

SUPPLEMENTAL INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
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Foreign Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Publication Date</u>	<u>Country or Patent Office</u>	<u>Translation</u>
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Other Documents

(including author, title, pertinent pages, etc.)

Examiner
Initial*

XN 1

Semiconductor lasers and related properties, identified as non-patent document 10 in application, obtained from <http://laserfocusworld.365media> on June 24, 2003.

References Cited by Applicants

While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

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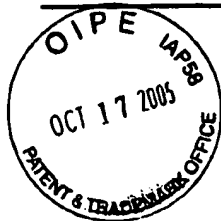
Examiner:	/Xinning Niu/	Date Considered:	02/21/2007
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INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANT

U.S. Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
<u>XN</u> 1	5,036,220	07/30/1991	Byer et al.

Foreign Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Publication Date</u>	<u>Country or Patent Office</u>	<u>Translation</u>
<u>XN</u> 2	6-194343	07/15/1994	Japan	No
<u>XN</u> 3	4-507299	12/17/1992	Japan	Yes
<u>XN</u> 4	6-175180	06/24/1994	Japan	No
<u>XN</u> 5	2002-139428	05/17/2002	Japan	No

Other Documents

(including author, title, pertinent pages, etc.)

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<u>XN</u> 6	K. Kubo et al., <i>Spin and Polarization</i> , BAIFUKAN, October 31, 1994, pp. 21-24 (with English translation).
<u>XN</u> 7	Harold J. Metcalf et al., <i>Laser Cooling and Trapping</i> , table, Springer, 1999, pp. 274.
<u>XN</u> 8	George Patterson et al., <i>Fluorescent Protein Spectra</i> , Journal of Cell Science, No. 114, Vol. 5, 2001, pp. 837-838.
<u>XN</u> 9	Arkady F. Fradkov et al., <i>Far-red Fluorescent Tag for Protein Labelling</i> , Journal of Biochem, No. 368, 2002, pp. 17-21.

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- XN 10 Dmitriy M. Chudakov, et al., *Kindling Fluorescent Proteins for Precise in Vivo Photolabeling*, Technical Report, Vol. 21, February 2003, pp. 191-194.
- XN 11 Dirk Richter et al., *Development of an Automated Diode-Laser-Based Multicomponent Gas Sensor*, Applied Optics, Vol. 39, No. 24, August 20, 2000, pp. 4444-4450.
- XN 12 Ioulia B. Zotova et al., *Reductions of Threshold for a Mid-Infrared Optical Parametric Oscillator by an Intracavity Optical Amplifier*, Optics Letters, Vol. 28, No. 7, April 1, 2003, pp. 552-554.
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- XN 14 A. Yariv, *Quantum Electronics*, Third Edition, Chapter 16.5, 1988, pp. 392-397.
- XN 15 Richard M. Schotland et al., *The Determination of the Vertical Profile of Atmospheric Gases by Means of a Ground Based Optical Radar*, Third Symposium on Remote Sensing of Environment, 1964, pp. 215-224.
- XN 16 M. H. Chou et al., *1.5 μ m-Band Wavelength Conversion Based on Cascaded Second-Order Nonlinearity in LiNbO₃ Waveguides*, IEEE Photonics Technology Letters, Vol. 11, No. 6, June 1999, pp. 653-655.
- XN 17 Osamu Tadanaga et al., *Highly-damage-resistant Quasi-phase-matched Wavelength Converter Using ZnO-doped LiNbO₃*, Proceedings of the 15th Annual Meeting of Institute of Electrical and Electronic Engineers, Lasers and Electro-Optics Society, Vol. 1, 2002 (IEOS2002), pp. 79-80.
- XN 18 H. Moosmuller et al., *Sum-frequency generation of Continuous-wave Sodium D₂ Resonance Radiation*, Optics Letters, Vol. 22, No. 15, August 1, 1997, pp. 1135-1137.
- XN 19 Toshitsugu Ueda et al., *Spectroscopic Detection of Gas Using Diode-Pumped Difference-frequency Generation*, Collection of Symposium Lecture Delivered by Measurement Automatic Control Institute, 2004, pp. 24-256 (with English translation).
- XN 20 Y. K. Sin et al., *Laterally Coupled InGaAsP/InP Distributed Feedback Lasers at 1.5 μ m for Chemical Sensing Applications*, Electronics Letters, Vol. 37, No. 9, April 26, 2001, pp. 567-569.

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- XN 22 A list of semiconductor lasers and their corresponding wavelength bands and other properties as available at time of preparing application and as identified as non-patent document 10 at pages 19 and 27 of the filed English translation of the present application.

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